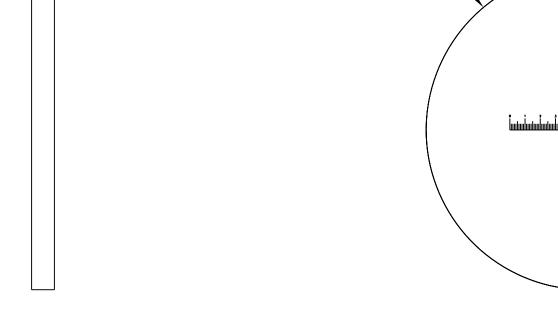
	MAX LEVY AUTOGRAPH, INC. PROPRIETARY	DATE	SYM	REVISION RECORD	AUTH	DR	СК			
	DO NOT DISCLOSE NOR DUPLICATE FOR OTHERS EXCEPT AS	3/11/02	А	ADDED EDMUND P/N, PATTERN DIA. CHANGED TITLE, AND CORRECTED LINE WIDTH SPECS	TEN	\Box				
		8/17/06	В	CHANGE "LOOKING THROUGH" TO "LOOKING AT"	ss					
					ł					
1.50mm±0.10mm [0.059"±0.004"]										
Ø21.00mm±0.10mm [Ø0.827"±0.004"]——										



NOTES:

- 1. BEVEL: REMOVE SHARP EDGES.
- 2. SURFACE FLATNESS: 3-4 WAVES
- 3. SURFACE QUALITY: SCRATCH:DIG 20:10 OVER ACTIVE AREA
- 4. PARALLELISM: < 30 ARCSEC
- 5. PATTERN OVERALL DIMESIONAL ACCURACY: 0.00004" (0.001MM)
- 6. PATTERN TO BE CENTERED ON SUBSTRATE ±0.004" (±0.10MM)
- 7. PATTERN LINEWIDTH IS 0.00059" ±0.0001" (0.015MM ±0.0025MM)
- 8. PATTERN ORIENTATION: RIGHT READING LOOKING AT.
- 9. COATING: LOW REFLECTION CHROMIUM FIRST SURFACE. CHROMIUM ADHESION LAYER WITH A TOP LAYER OF CHROMIUM OXIDE, OPTICAL DENSITY > 3.0. COATING DESIGNED TO PROVIDE REFLECTION < 5% @ 550 NM
- 10 PATTERN
 - 10MM / 100 DIVISIONS
- 11. PACKAGING: BAG AND TAG PER 700MLA0060-001
- 12. PATTERN DIAMETER: 10.348MM

MLO PART NUI	MBER: AA015 EDMUND P/N		54245	ONLINE CATALOG RD2055					
TOLERANCES (EXCEPT AS NOTED)	MAX LEVY AUTOGRAPH								
DECIMAL .XXX= +/005 .XX= +/015 .X= +/030	SODA LIM	1E GLASS	NON	TEN APPROVED BY					
+/030	1X MICROSCOPE CALIBRATION RETICLE, METRIC								
angular +/-0.5Deg.	12-19-00	DRAWING NUMBER	ML	A0072A-015					